



SMD Comm X8G HT150C, Ceramic, 1.3 pF, +/-0.5 pF, 250 VDC, X8G, SMD, MLCC, High Temperature, Ultra-Stable, 0603, 0.5 mm



General Information	
Series	SMD Comm X8G HT150C
Style	SMD Chip
Description	SMD, MLCC, High Temperature, Ultra-Stable
Features	High Temperature, Ultra-Stable
RoHS	Yes
Termination	Tin
Marking	No
AEC-Q200	No
Typical Component Weight	3.7 mg
Shelf Life	78 Weeks
MSL	1

Dimensions	
Chip Size	0603
L	1.6mm +/-0.15mm
W	0.8mm +/-0.15mm
Т	0.8mm +/-0.07mm
S	0.5mm MIN
В	0.35mm +/-0.15mm

<u> </u>	1.6mm +/ -0.15mm	Measurement Condition	I MHZ I.OVrms
W	0.8mm +/-0.15mm	Tolerance	+/-0.5 pF
Т	0.8mm +/-0.07mm	Voltage DC	250 VDC
5	0.5mm MIN	Dielectric Withstanding Voltage	625 VDC
В	0.35mm +/-0.15mm	Temperature Range	-55/+150°C
		Temp. Coefficient	X8G
Packaging Specifications		Capacitance Change with	30 ppm/C, 1MegaHz 1.0Vrms
Packaging	T&R, 330mm, Paper Tape	Reference to +25°C and 0 VDC Applied (TCC)	., , , ,
Packaging Quantity	15000	Dissipation Factor	0.1% 1 MHz 1.0Vrms

Specifications	
Capacitance	1.3 pF
Measurement Condition	1 MHz 1.0Vrms
Tolerance	+/-0.5 pF
Voltage DC	250 VDC
Dielectric Withstanding Voltage	625 VDC
Temperature Range	-55/+150°C
Temp. Coefficient	X8G
Capacitance Change with Reference to +25°C and 0 VDC Applied (TCC)	30 ppm/C, 1MegaHz 1.0Vrms
Dissipation Factor	0.1% 1 MHz 1.0Vrms
Aging Rate	0% Loss/Decade Hour: Referee Time is 1000 Hours
Insulation Resistance	100 GOhms

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